

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: A1608-02	DATE: 6-Sep-2016	MEANS OF DISTINGUISHING CHANGED DEVICES:				
Product Affected: 4DB0226KA3ZAV (built in FCCSP-53)	· ,	 Product Mark Back Mark Date Code Other Lot # will have: "SL" prefix for SFA, Korea 				
Date Effective: 6-Dec-2016						
Contact: IDT PCN DESK		Attachment: Yes No				
E-mail: <u>pcndesk@idt.com</u>		Samples: Please contact your local sales representative for sample request.				
DESCRIPTION AND PURPOSE OF C	HANGE:					
 Die Technology Wafer Fabrication Process Assembly Process Equipment Material Testing Manufacturing Site Data Sheet Other This notification is to advise our customers that IDT is adding SFA Semicon Co. Ltd, Korea (previously named as STS Semiconductor & Telecommunication Co. Ltd) as an alternate assembly facility for parts that are currently assembled at ASEK and ASECL, Taiwan. There is no change to the moisture performance. Attachment I details the qualification results. 						
RELIABILITY/QUALIFICATION SU Refer to qualification data shown in Attac						
CUSTOMER ACKNOWLEDGMENT OF RECEIPT: IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable. IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.						
Customer:	C	Approval for shipments prior to effective date.				
Name/Date:	Date: E-Mail Address:					
Title:	Phone# /Fax# :					
CUSTOMER COMMENTS:						
IDT ACKNOWLEDGMENT OF RECI	EIPT:					
RECD. BY:		DATE:				



Integrated Device Technology, Inc. 6024 Silver Creek Valley Road, San Jose, CA - 95138

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ATTACHMENT I - PCN # : A1608-02

PCN Type:	Manufacturing Site - Alternate Assembly Location				
Data Sheet Change:	None				
	No change in moisture sensitivity level (MSL)				

Detail Of Change:

This notification is to advise our customers that IDT is adding SFA Semicon Co. Ltd, Korea (previously named as STS Semiconductor & Telecommunication Co. Ltd) as an alternate assembly facility for parts that are currently assembled at ASEK and ASECL, Taiwan.

The material set details of the current and alternate assembly location is as shown in Table 1.

There is no change to the moisture performance.

Table 1: Assembly Material Sets for The Existing and Alternate Assembly Location

	Existing Assembly (ASE Kaohsiung, Taiwan & ASE Chungli, Taiwan)	Alternate Assembly (SFA, Korea)	
Die Bump	Sn1.8Ag	Sn1.8Ag	
Mold Compound	KE-G1250FC-20B	Panasonic CV8710U	
Substrate	ABF-GX13/E700GR core	ABF-GX13/E700GR core	
Solder Balls	Sn98.25/Ag1.2/Cu0.50/Ni0.05	Sn98.25/Ag1.2/Cu0.50/Ni0.05	



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Qualification Information and Qualification Data:

- Affected Packages: FCCSP-53
- Assembly Material: Shown on page 2 of this attachment.
- Qual Plan & Results: Tests are in accordance with JEDEC47 recommended tests.

Qualification Vehicle: FCCSP-53

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Test Description	Test Method	Test Results (Rej / SS)		
Test Description	i est Miethou	Lot 1	Lot 2	Lot 3
* Temperature Cycling (-55°C to 125°C, 700 cycles)	JESD22-A104	0/25	0/25	0/25
* HAST - biased (130 °C/85% RH, 96 Hrs)	JESD22-A110	0/25	0/25	0/25
High Temperature Storage Bake (150°C, 1000 Hrs)	JESD22-A103	0/25	0/25	0/25
Solder Ball Shear Test	JESD22-B117	0/5	0/5	0/5
Moisture Sensitivity Level, MSL	J-STD-20 / MSL 3, 260 °C	0/25	0/25	0/25

Tests were subjected to Preconditioning per JESD22-A113 prior to stress test